



INTERNATIONAL
ELECTROTECHNICAL
COMMISSION



International standardization on graphene and other 2D materials: Status and future prospects

Recent Progress in Graphene & 2D Materials Research, RPGR 2017,
Singapore, September 18-22, 2017



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IEC/TC 113: NANOTECHNOLOGY FOR ELECTROTECHNICAL
PRODUCTS AND SYSTEMS

Standardization is one of the key issues for the industrialization of graphene enabled products

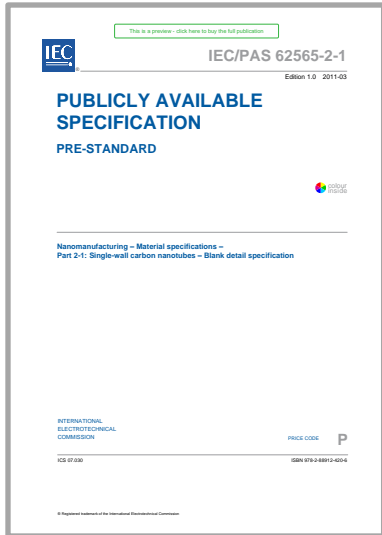
- **October 2012: IEC/TC 113 held a workshop about “graphene” as a new field of interest in Milpitas, CA, USA**
- **October 2013: Establishment of the Graphene Flagship - No need for standardization stated**
- **October 2014: Standardization as part of an open call in the Graphene Flagship**
- **October 2017: IEC/TC 113 has a track record on 19 workshops and invited talks regarding graphene standardization at international conferences**

Standardization is one of the key issues for the industrialization of graphene enabled products

- **Introductory remarks on standardization**
- **IEC/TC 113: The one-stop-shop for graphene standardization**
- **The international graphene standardization landscape**
- **Blank Detail Specifications and Key Control Characteristics measurement standards**
- **Future prospects: Standardization along the value adding chain**



Standards



- Formal consensus based document developed by a Standard Developing Organization (SDO)
- SDOs provides consensus processes and rules to develop standards.
- SDOs provides maintaining procedures to ensure that standards at any time represents the state of the art of technology.
- Technical content of standards is within the responsibility of technical experts active in project teams of the SDO.
- IEC/ISO work according to the WTO Standards Code



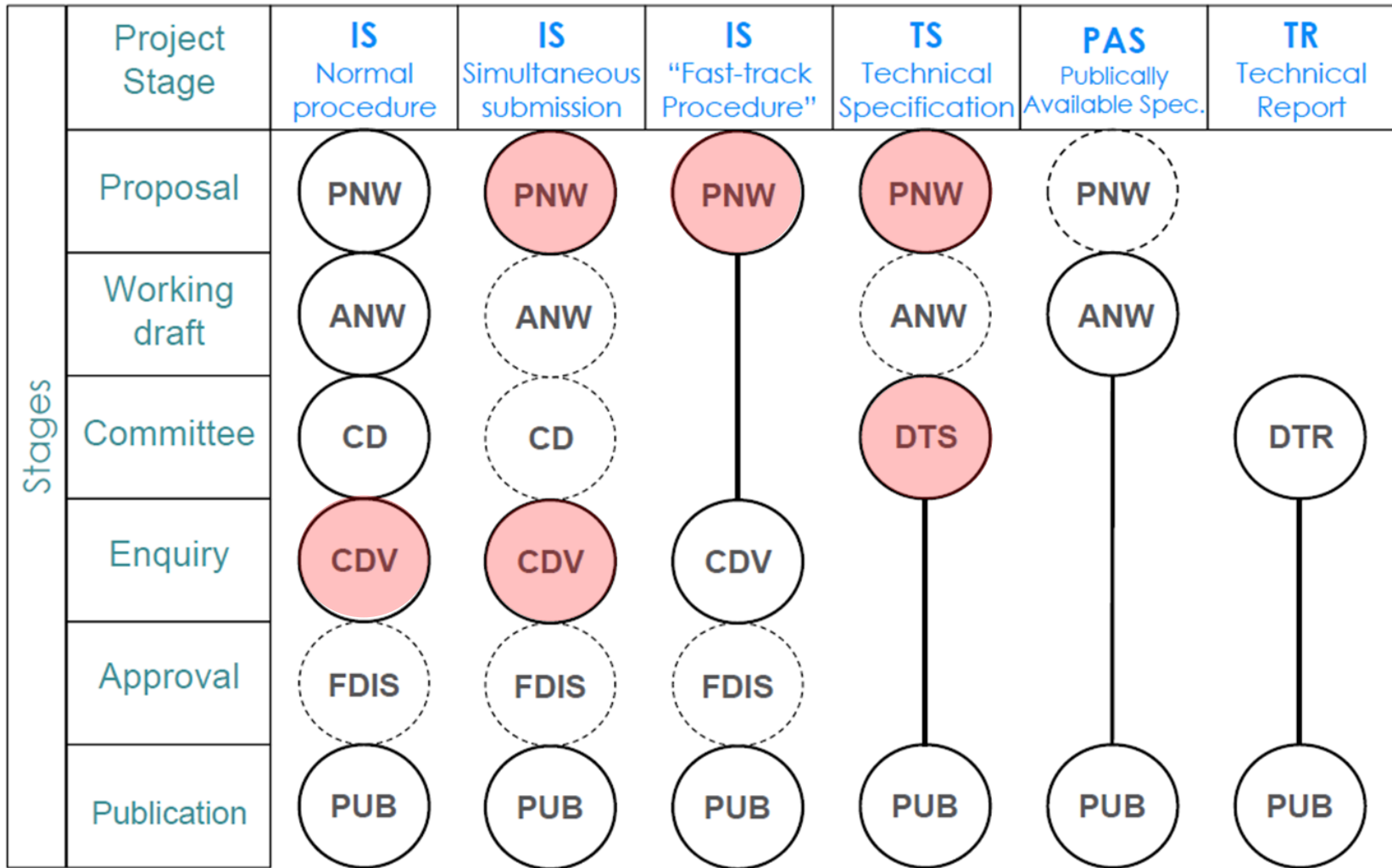


Success Factors:

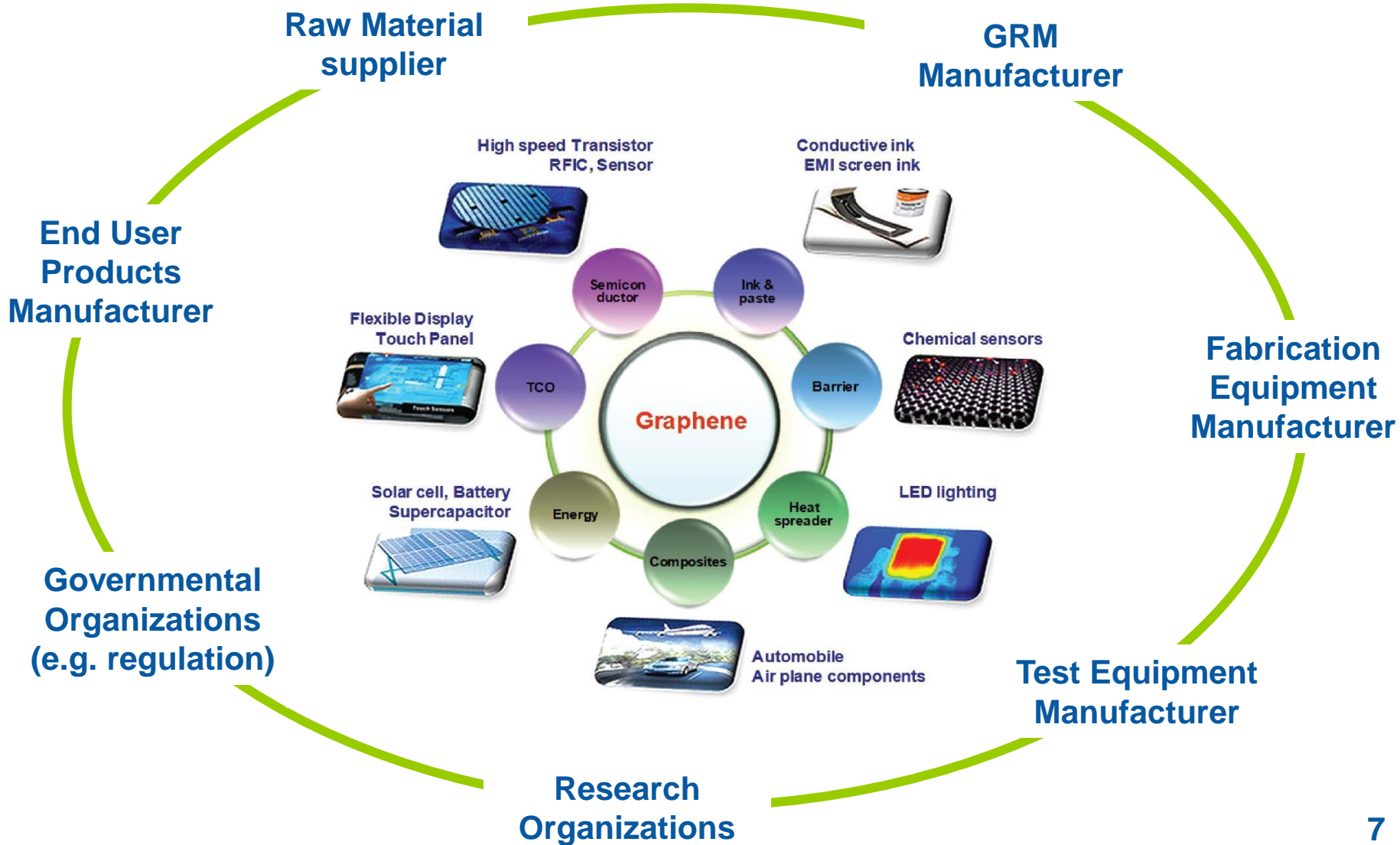
- Technical maturity of the content
- Engagement of technical experts
- Number of meetings:
 - 2 Face-to-face meetings per year
 - Online in between
- Not reinvent the wheel:
 - Prevent double work
 - Use or adopt-and-modify existing standards



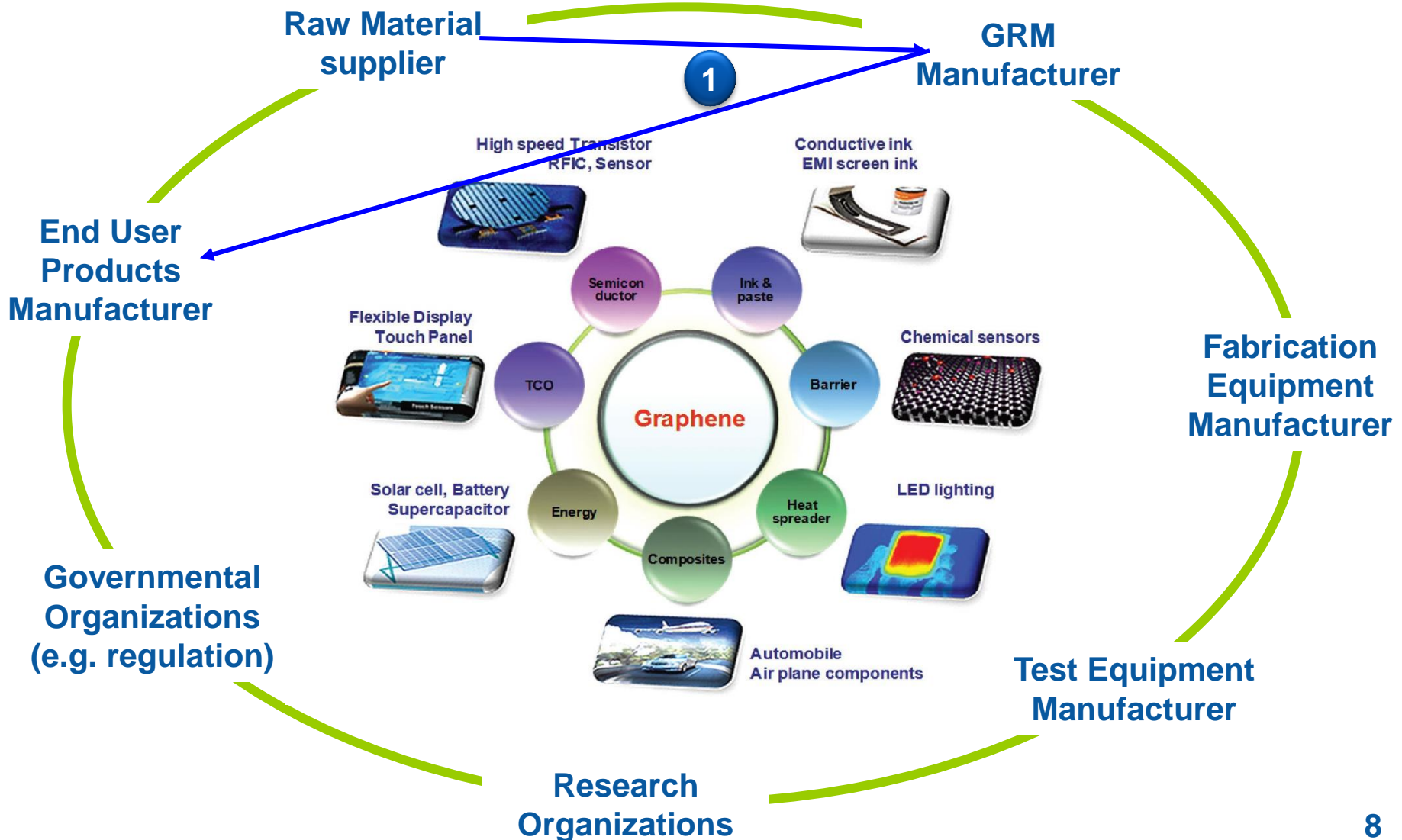
The IEC/ISO process



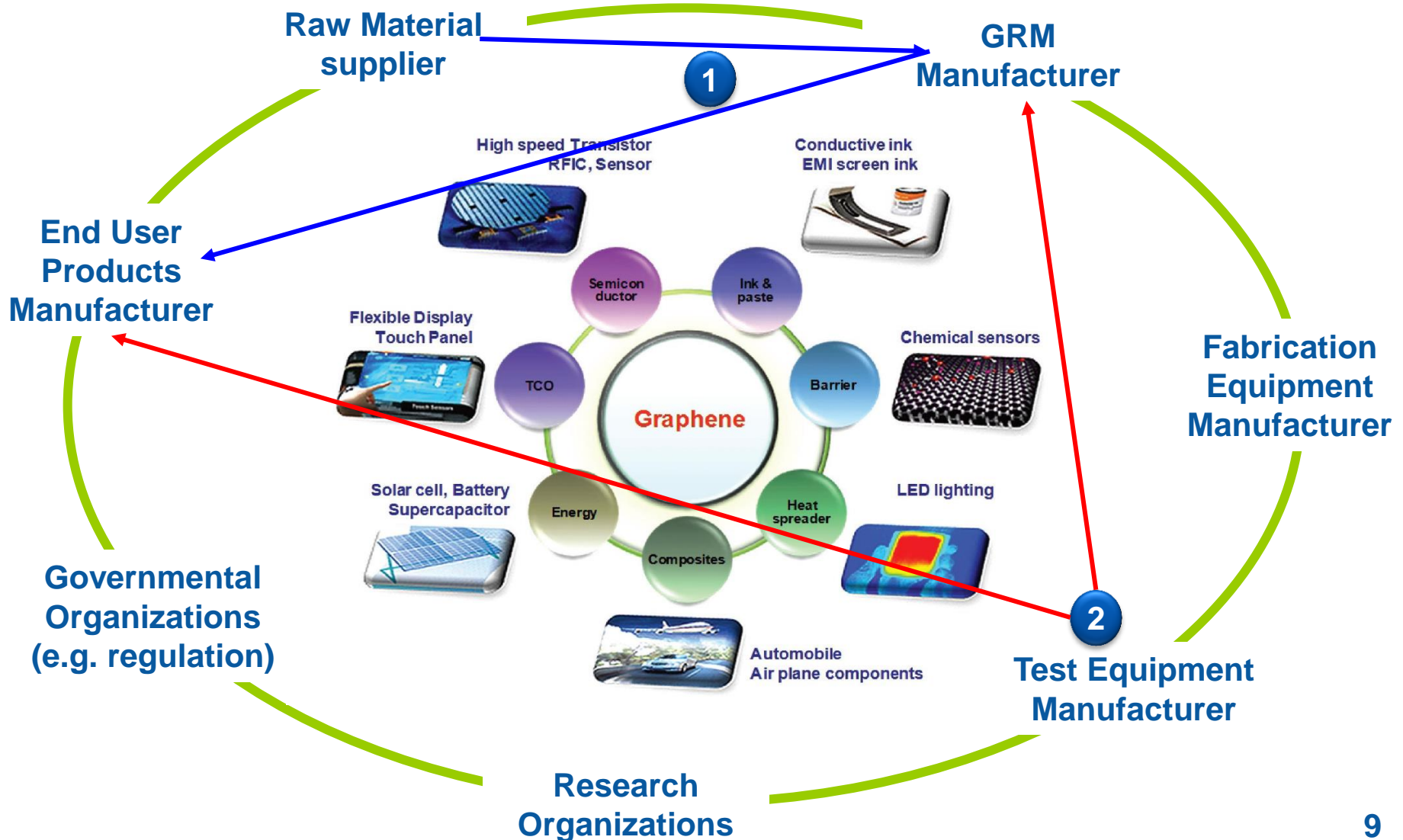
Stakeholder regarding graphene standardization



Example 1: Standardized specifications supports the supply chain



Example 2: Measurement standards supports equipment availability



If a company is part of a well established network based on close and long term bilateral co-operations:

- **There is no need for standardization**
- **Those companies typically try to impede standardization**

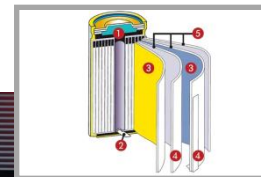
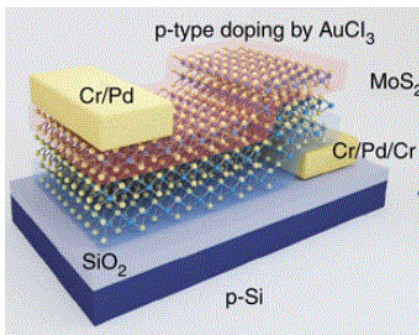
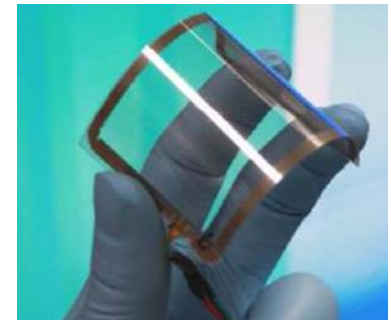
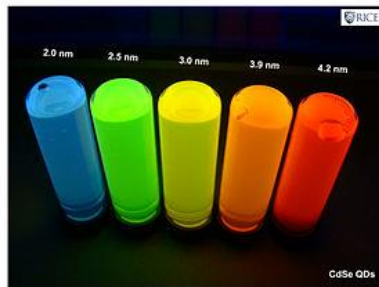
If a company wants to work with alternating suppliers to take profit from the competition among their suppliers

- **They strongly depend from reliable standardized specifications**
- **Those companies support standardization**

The experience is that companies who are active participating on standardization are more successful on the long term

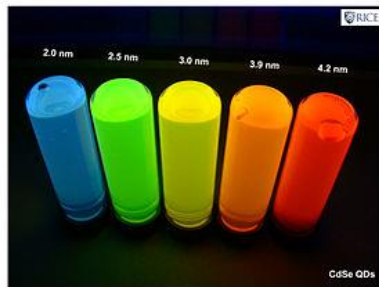
Title and scope of IEC/TC 113

- **TC 113 – Nanotechnology for electrotechnical products and systems**
- **Standardization of the technologies relevant to electrotechnical products and systems in the field of nanotechnology in close cooperation with other committees of IEC and ISO.**



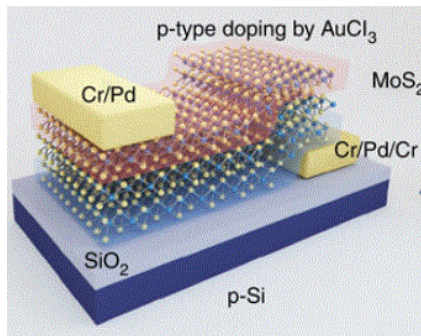
Nano-enabled electrotechnical product: “electrotechnical product exhibiting function or performance only possible with nanotechnology”

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IEC/TC 113 projects:

- **Total under work: 37**
- **Total published: 29**
- **Topics**
 - Carbon nanomaterials
 - Luminescent nanomaterials
 - Nanoscale contacts
 - Nano-enabled PV
 - Nano-enabled energy storage
 - Nanoelectronics



Nano-enabled electrotechnical product: “electrotechnical product exhibiting function or performance only possible with nanotechnology” 12

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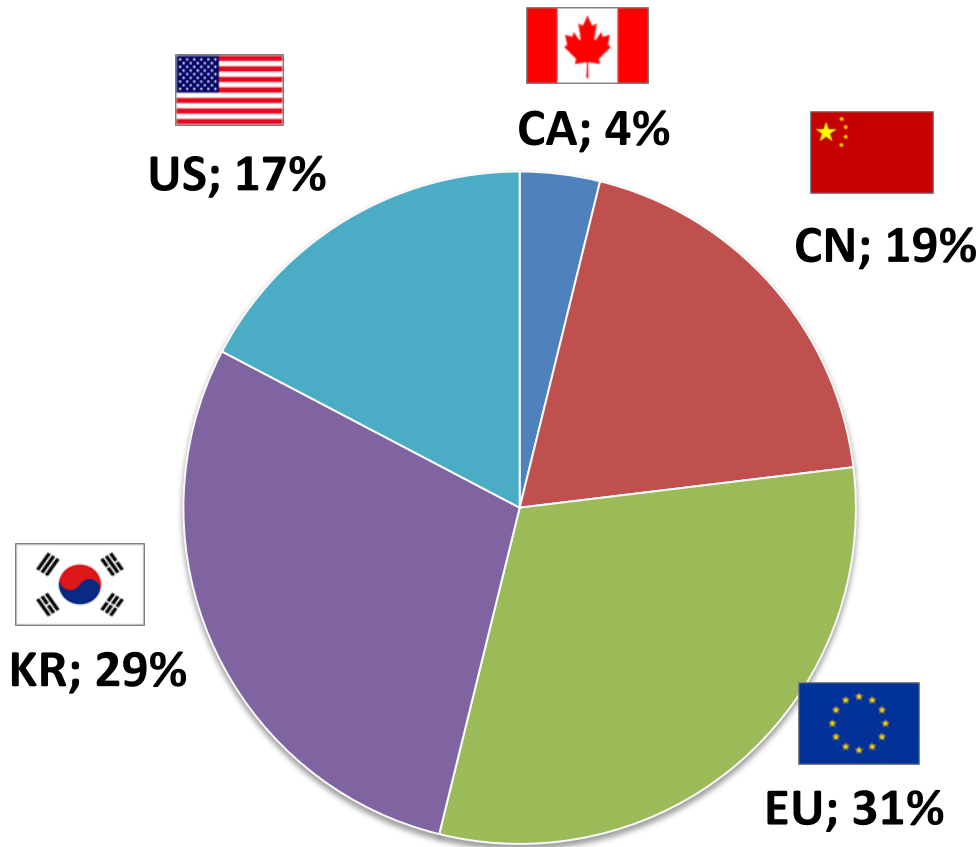
Graphene related materials: WG 8

22 (+4 in the definition phase)

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Nano-enabled electrotechnical product: “electrotechnical product exhibiting function or performance only possible with nanotechnology”

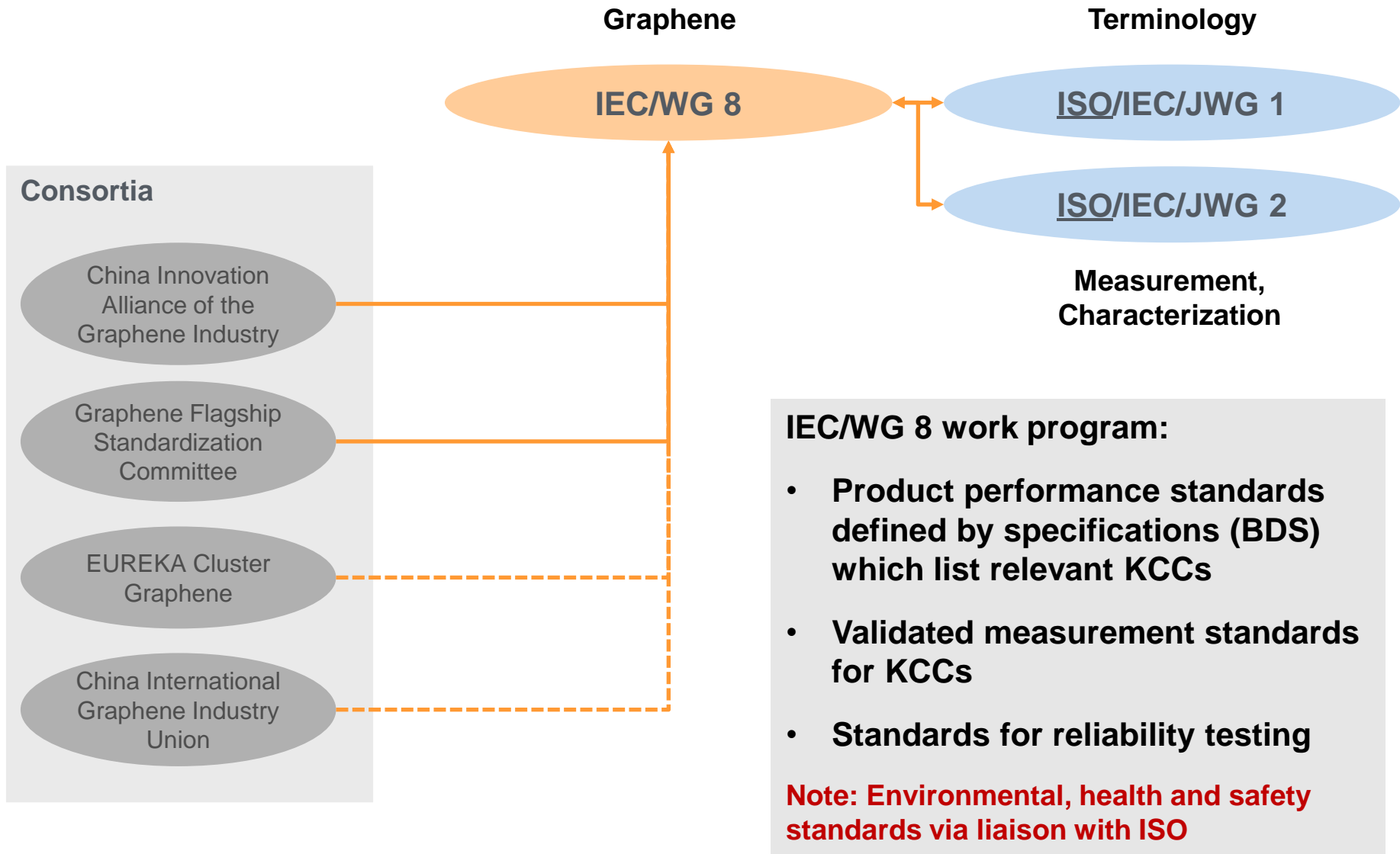


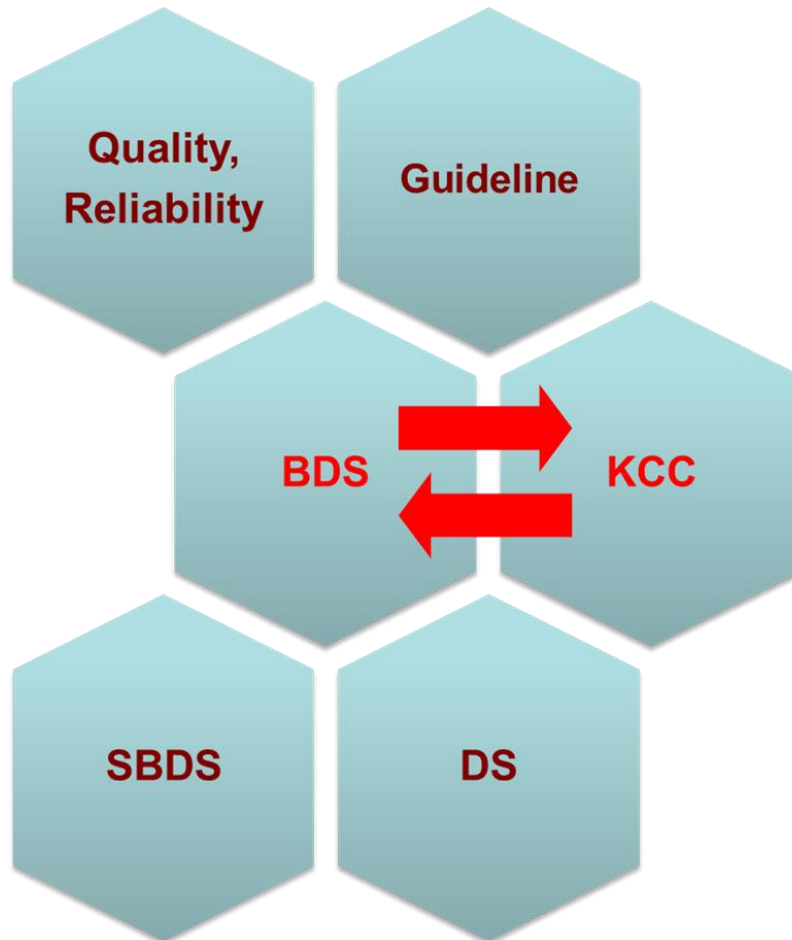
Project leadership by countries (world wide)

Graphene projects IEC/ISO:

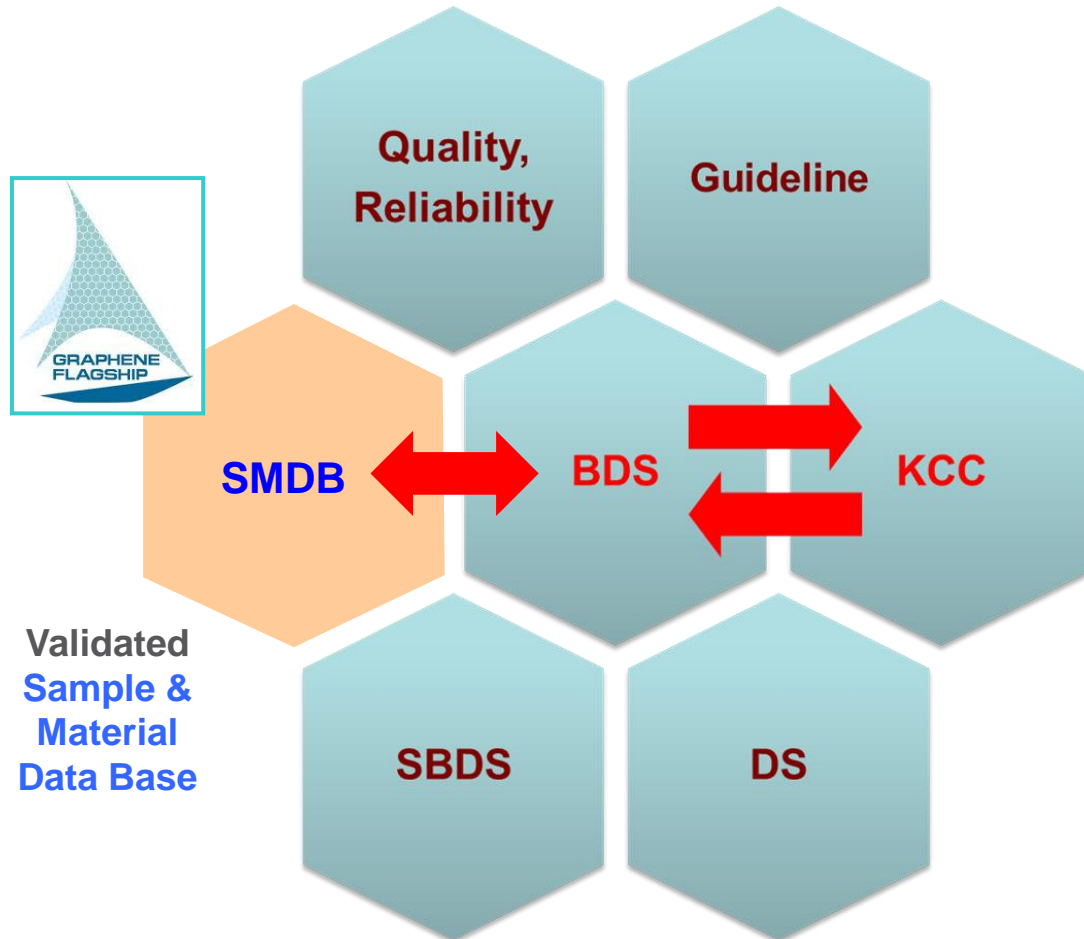
- 10/2014: Europe 17%
 - Start of standardization activities in the graphene flagship 10/2014
- 03/2016: Europe 50%
 - China joined 05/2016
- 10/2016: Europe 36%
- 03/2017: Europe 30%
- 10/2017: Europe 31%
China 19%

- Published: 2 (IEC/ISO)
- Majority led by IEC





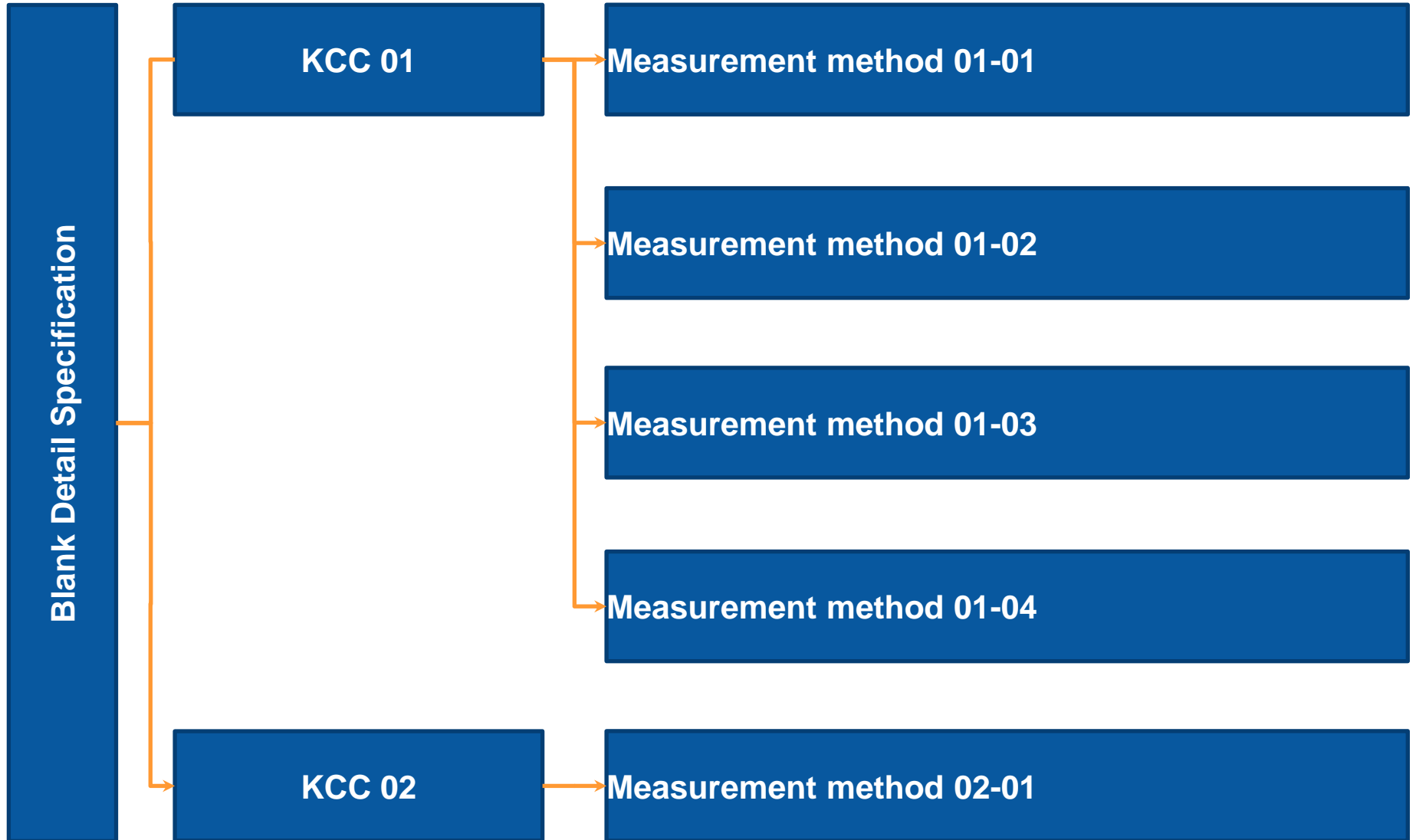
- **BDS: Blank Detail Specification** lists the KCCs and the related measurement methods
- **KCC: Measurement standards for Key Control Characteristics**
- **Guideline: Guiding documents** to write specifications
- **SBDS: Sectional Blank Detail Specifications**
- **DS: Detail Specifications for special applications**
- **Quality, Reliability: Standards** regarding quality and reliability assessment



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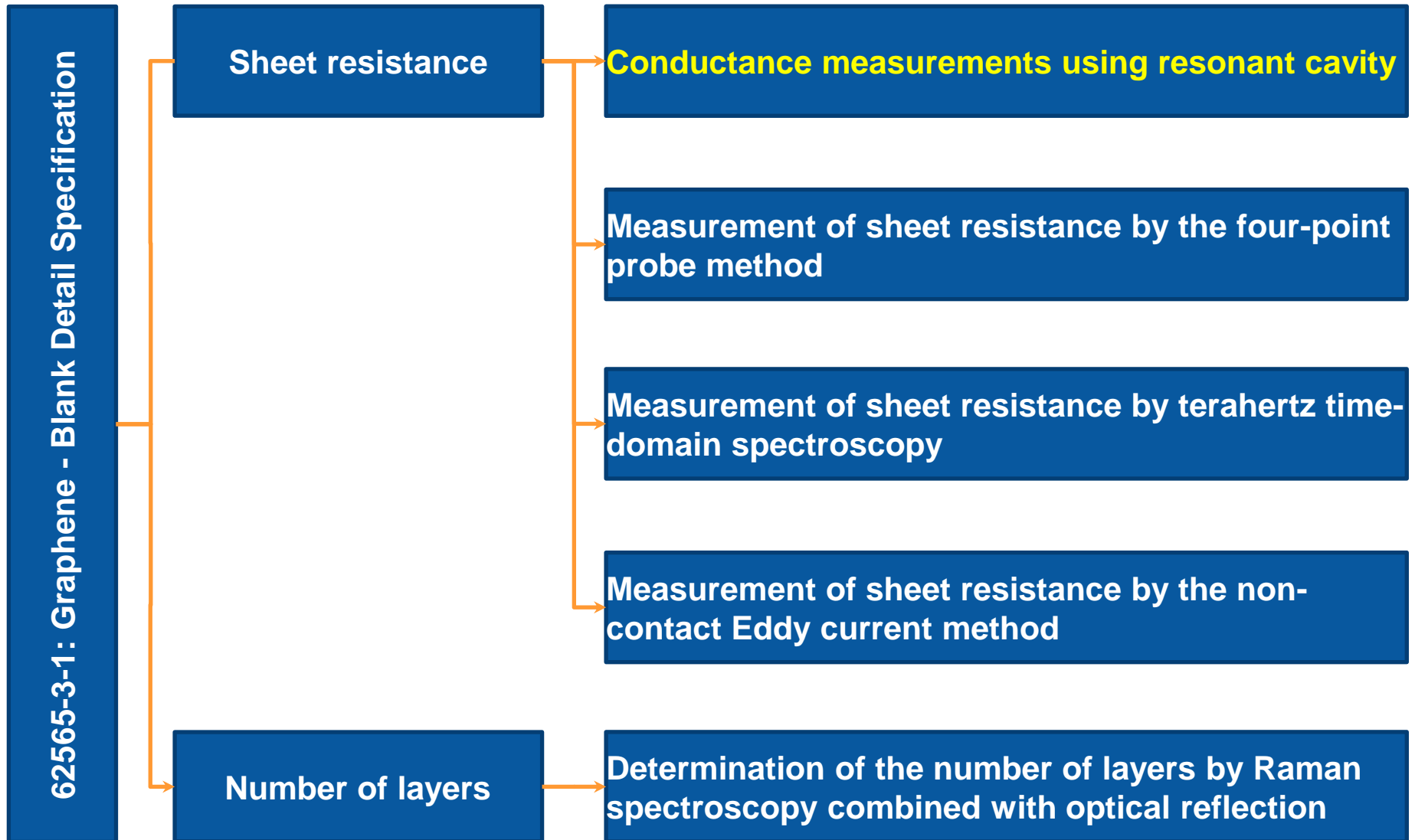


IEC 62565-3-1: Blank Detail Specification Graphene (Principle)





IEC 62565-3-1: Blank Detail Specification Graphene (Example)





Content of IEC 62565-3-1 Blank Detail Specification Graphene

FOREWORD

INTRODUCTION

1 Scope

2 Normative references

3 **Terms, definitions**

3.1 General graphene terms (Ref. 80004-13)

3.2 Terms related to procurement

3.3 Terms related to material description

3.4 Chemical key control characteristics

3.5 Electrical key control characteristics

3.6 Thermal key control characteristics

3.7 Optical key control characteristics

3.8 Mechanical key control characteristics

3.9 Structural and dimensional key control characteristics

4 Measurement methods

5 **Graphene specification format and recommended measurement methods**

5.1 Procurement information

5.2 General material description

5.3 Chemical key control characteristics

5.4 Electrical key control characteristics

5.5 Thermal key control characteristics

5.6 Optical key control characteristics

5.7 Mechanical key control characteristics

5.8 Structural and dimensional key control characteristics

Table 4 – Format for electrical key control characteristics

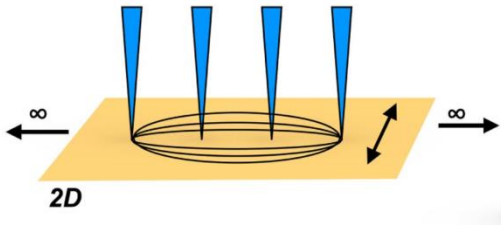
KCC No	KCC	Specification	Measurement method	F	P	D
4.1	Sheet resistance	Nominal [] ± Tolerance [] Ω/sq	IEC/TS 62607-06-04	✓		✓ ²
			IEC/TS 62607-06-08			
			IEC/TS 62607-06-09			
			IEC/TS 62607-06-10			
4.2	Sheet conductance	Nominal [] ± Tolerance [] S/sq	IEC/TS 62607-06-04	✓		✓ ²
4.3	Conductivity	Nominal [] ± Tolerance [] S/m	IEC/TS 62607-06-01		✓ ¹	
4.4	Field effect carrier mobility	Nominal [] ± Tolerance [] cm^2/Vs		✓		
4.5	Hall carrier mobility	Nominal [] ± Tolerance [] cm^2/Vs		✓		
4.6	Work function	Nominal [] ± Tolerance [] meV		✓		

Note

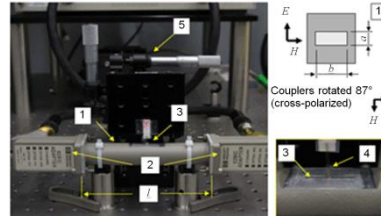
1) Measured on pellets

2) Measured on films solidified according to suppliers specification

Four point probe



Eddy current



Microwave cavity

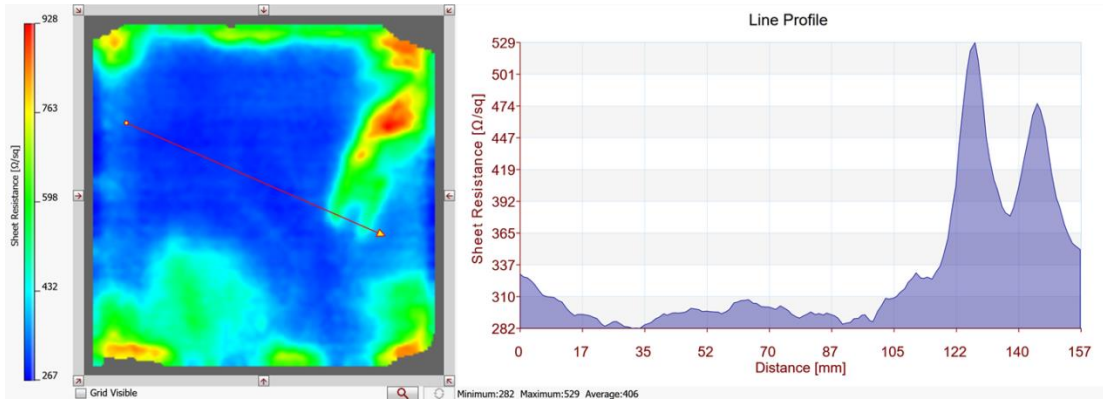


THz-TDS

Measurement method	F	P	D
IEC/TS 62607-06-04			
IEC/TS 62607-06-08	✓		✓ ²
IEC/TS 62607-06-09			
IEC/TS 62607-06-10			
IEC/TS 62607-06-04	✓		✓ ²
IEC/TS 62607-06-01		✓ ¹	
	✓		
	✓		
	✓		

published

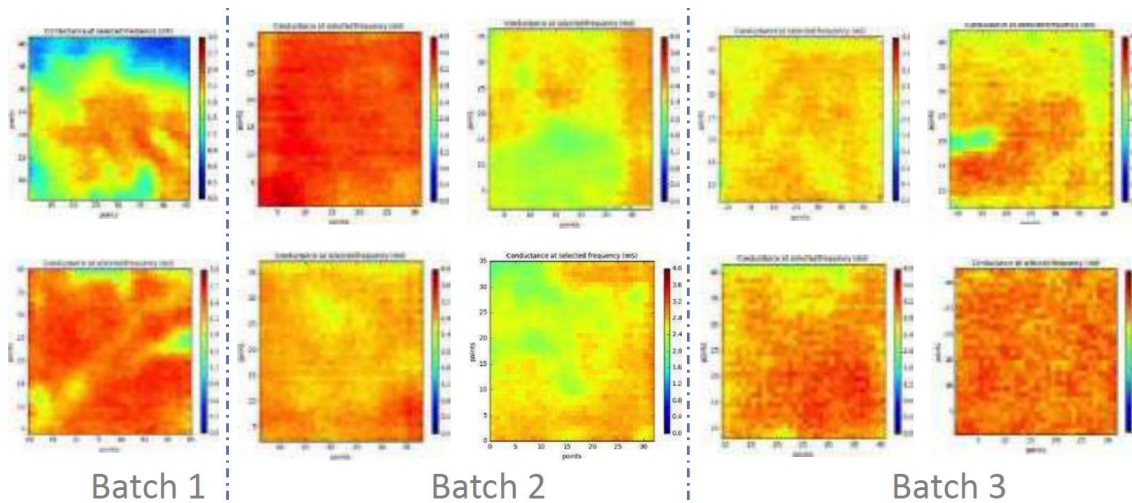
Example: Analysis of sheet resistance uniformity:



IECTS 62607-6-9
 With courtesy of:
 Suragus GmbH, Germany



Example: Analysis batch reproducibility:



IEC/TS 62607-6-10
 With courtesy of:
 das-Nano S.L., Spain



FOREWORD

INTRODUCTION

1 Scope

2 Normative references

3 Terms, definitions

4. General

4.1 Measurement principle

4.2 Measurement configuration

4.2.1 Transmission configuration

4.2.2 Reflection configuration *examples*

4.3 Measurement mode

4.3.1 Single point mode

4.3.2 Image scanning mode *examples*

4.4 Measurement system

4.4.1 Measurement equipment / apparatus

4.4.2 Materials

4.4.3 Calibration standards

4.4.4 Ambient conditions

4.4.5 Sample preparation method

5. Measurement procedure

5.1 Calibration of measurement equipment

5.2 Detailed protocol of the measurement procedure

5.3 Measurement accuracy

6. Data analysis / Interpretation of results

7. Results to be reported

ANNEX

A. Use case description

B. Sampling plan

C. Test report

D. Worked examples

Test Report

This test report concludes the results of sample characterization according to

IEC/TS 62607-6-10 NANOMANUFACTURING – KEY CONTROL CHARACTERISTICS – Part 10:

Graphene – Measurement of sheet resistance by terahertz time domain spectroscopy

1. Identification of test samples according to IEC 62565-3-1

Item No	Item
1.1	Supplier
1.2	Trade name
1.3	ID number
1.4	Traceability requirements
	<input type="checkbox"/> Batch number <input type="checkbox"/> Serial number <input type="checkbox"/> Others, specify Manufacturing date
1.5	Specification
	Number
	Revision level
	Date of issue

2. General material description according to 62565-3-1

Item No	Item	Information
2.1	Material type	
2.2	Physical form	<input type="checkbox"/> Film on substrate (F)
		<input type="checkbox"/> Powder (P)
		<input type="checkbox"/> Solution (S)
2.3	Composition	
2.4	Manufacturing method	
2.5	Transfer method	
2.6	Substrate	
2.7	Solvent	
2.8	Shelf life	Nominal [] s, d
2.9	Curing conditions*	
2.10	Material Safety Data Sheet (MSDS) available	<input type="checkbox"/> No
		<input type="checkbox"/> Yes, reference
2.11	Typical batch quantity	<input type="checkbox"/> Number of wafers
		<input type="checkbox"/> Weight [kg]
		<input type="checkbox"/> Volume [l]

3. Geometry of the sample

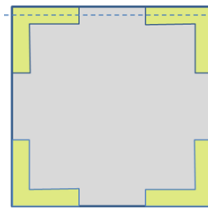


Figure 1: Top view

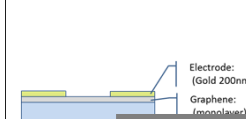


Figure 2: Cross section

4. Test related information

Item No	Item	Information
3.1	Sampling plan	<input type="checkbox"/> Circular, specify C.....
		<input checked="" type="checkbox"/> Square, specify S.....
		<input type="checkbox"/> others, drawing attached
3.2	Excitation wavelength	
3.3	Number of spectra/measurement	<input type="checkbox"/> 10x10
		<input type="checkbox"/> others, specify
3.4	I(D)/I(G)	<input type="checkbox"/> not visible
3.5	Mean value and standard deviation of FWHM(2D) distribution	
3.6	Raman maps	<input type="checkbox"/> attached
		<input type="checkbox"/> available on request
3.7	Environmental humidity	

5. KCC maps

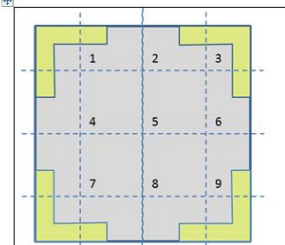


Figure 3: Sampling plan

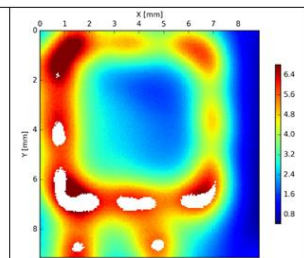


Figure 4: Conductivity map

6. KCC measurement results

Position	Surface conductivity	FET/Hall mobility
1		
2		
3		
4		
5		
6		
7		
8		
9		

Standardization process

Consensus:
„yes“ $\geq 66,7\%$
„no“ $\leq 25,0\%$

Stability:
1-3 years



Consensus:
„yes“ $\geq 66,7\%$
„no“ $\leq 25,0\%$

Stability:
1-3 years



Voting is performed by the IEC members (countries) after they have achieved a consensus position in their country

Standardization process

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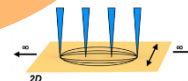
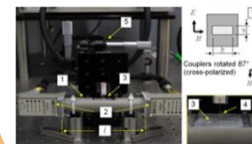


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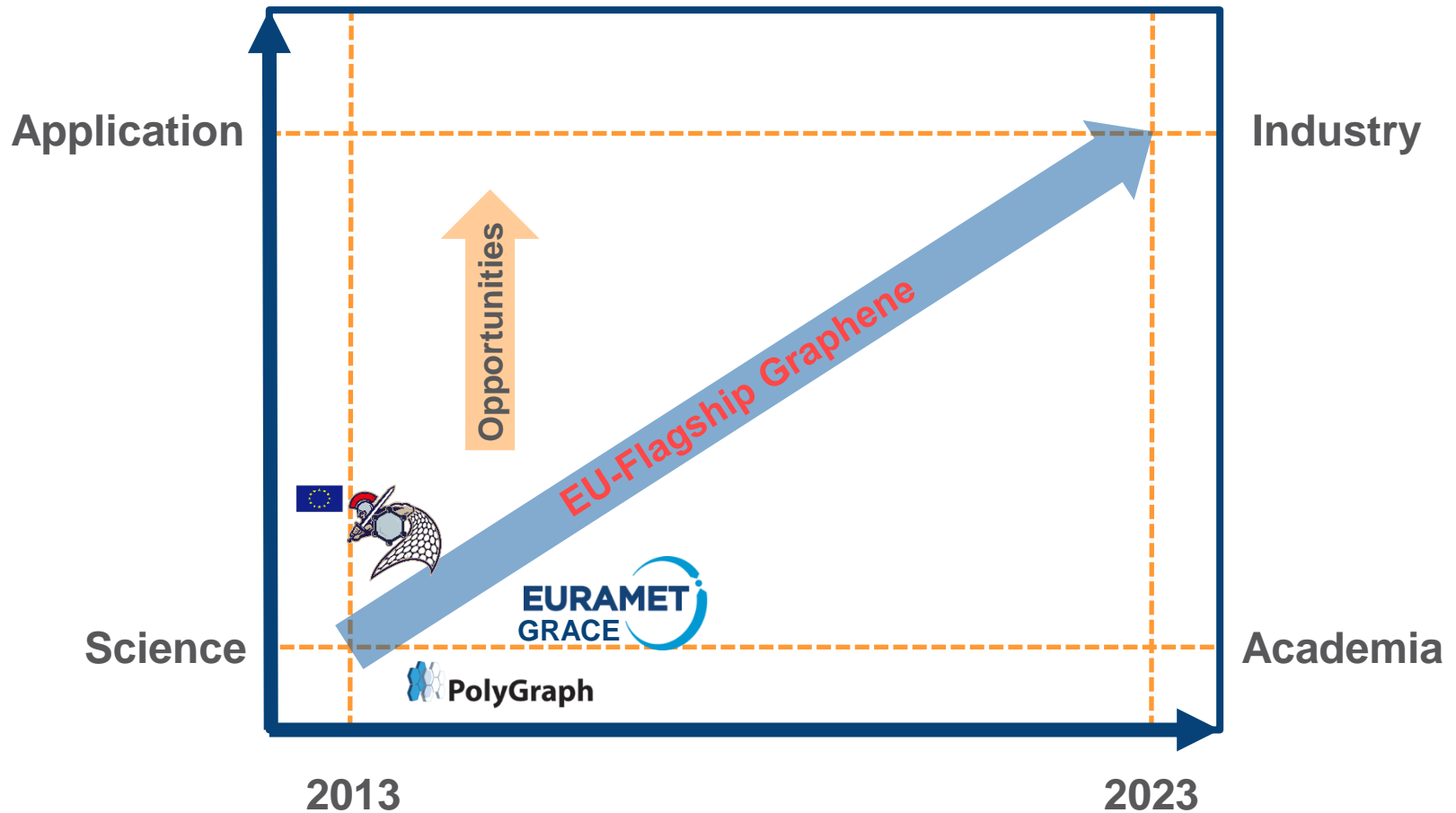
Stability:
1-3 years



Scientific validation (round robin):

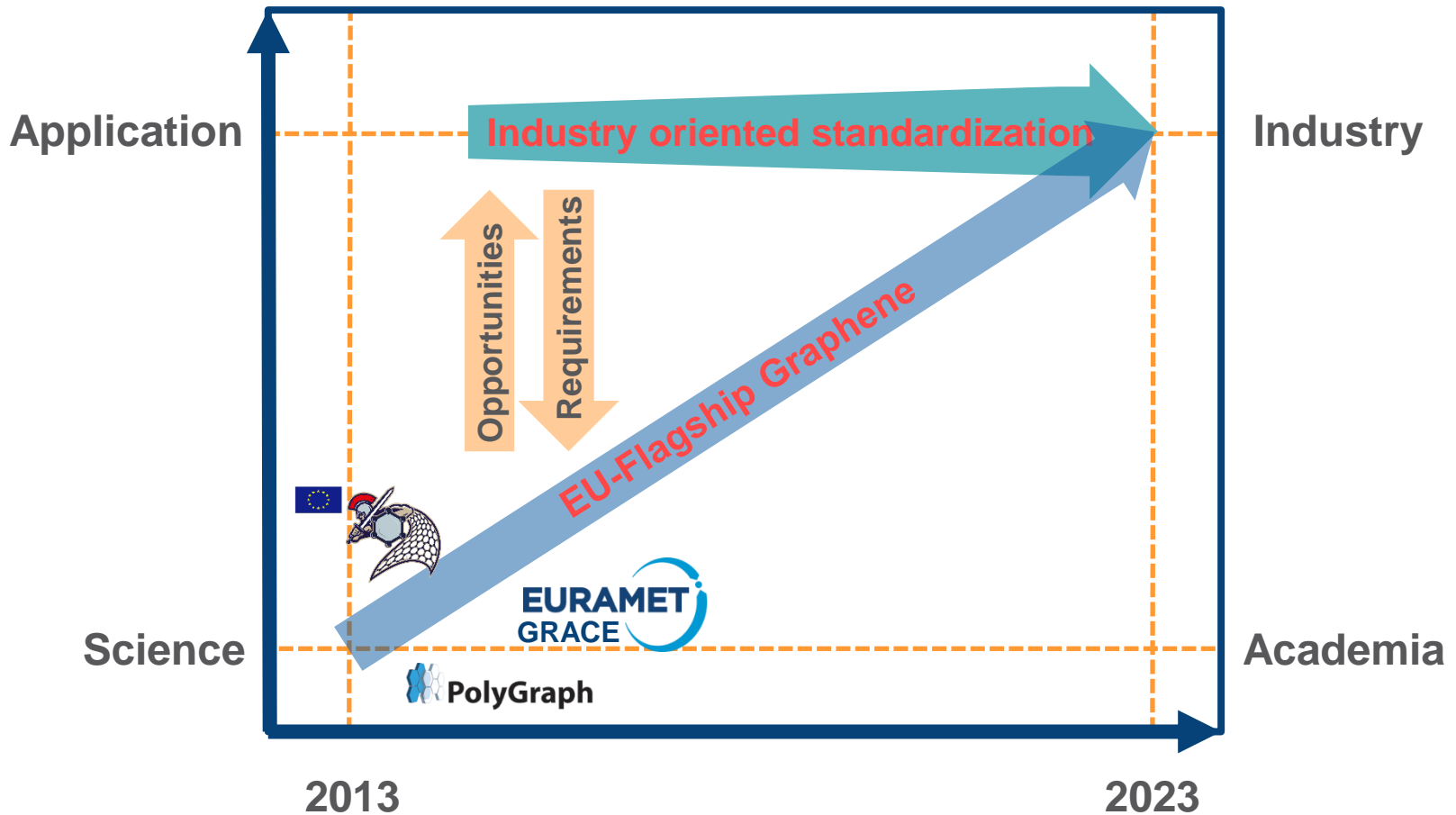


Moving towards industry oriented standardization



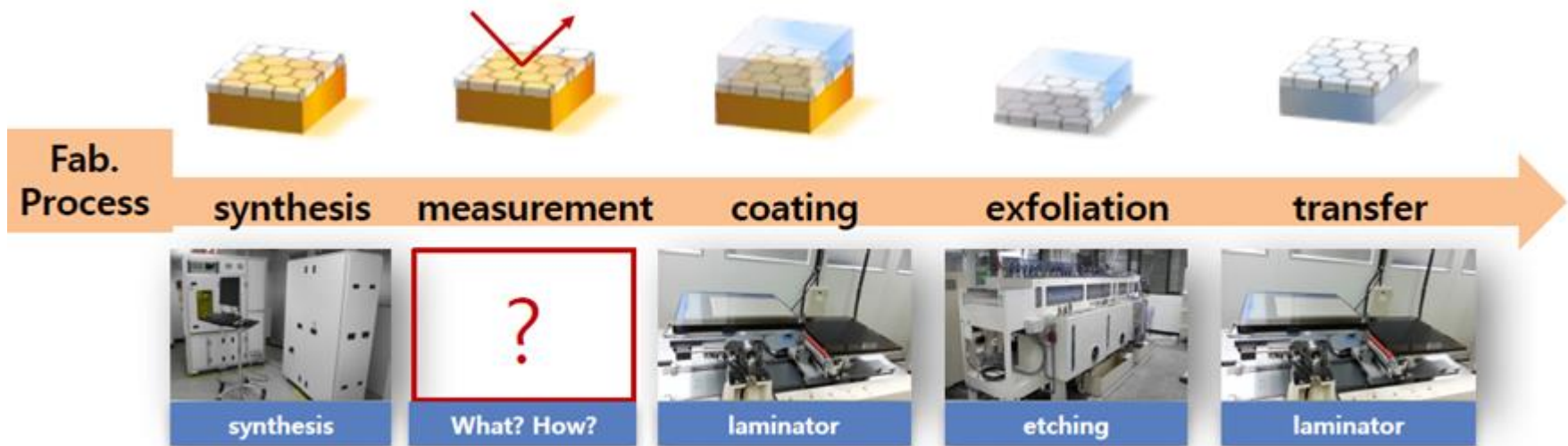
Standardization supports cooperation between the EU-Flagship and other EU projects like “Polygraph (FP7)”, “Gladiator (FP7)”, “GRACE” (Euramet EMPIR) as well as national funded projects.

Moving towards industry oriented standardization



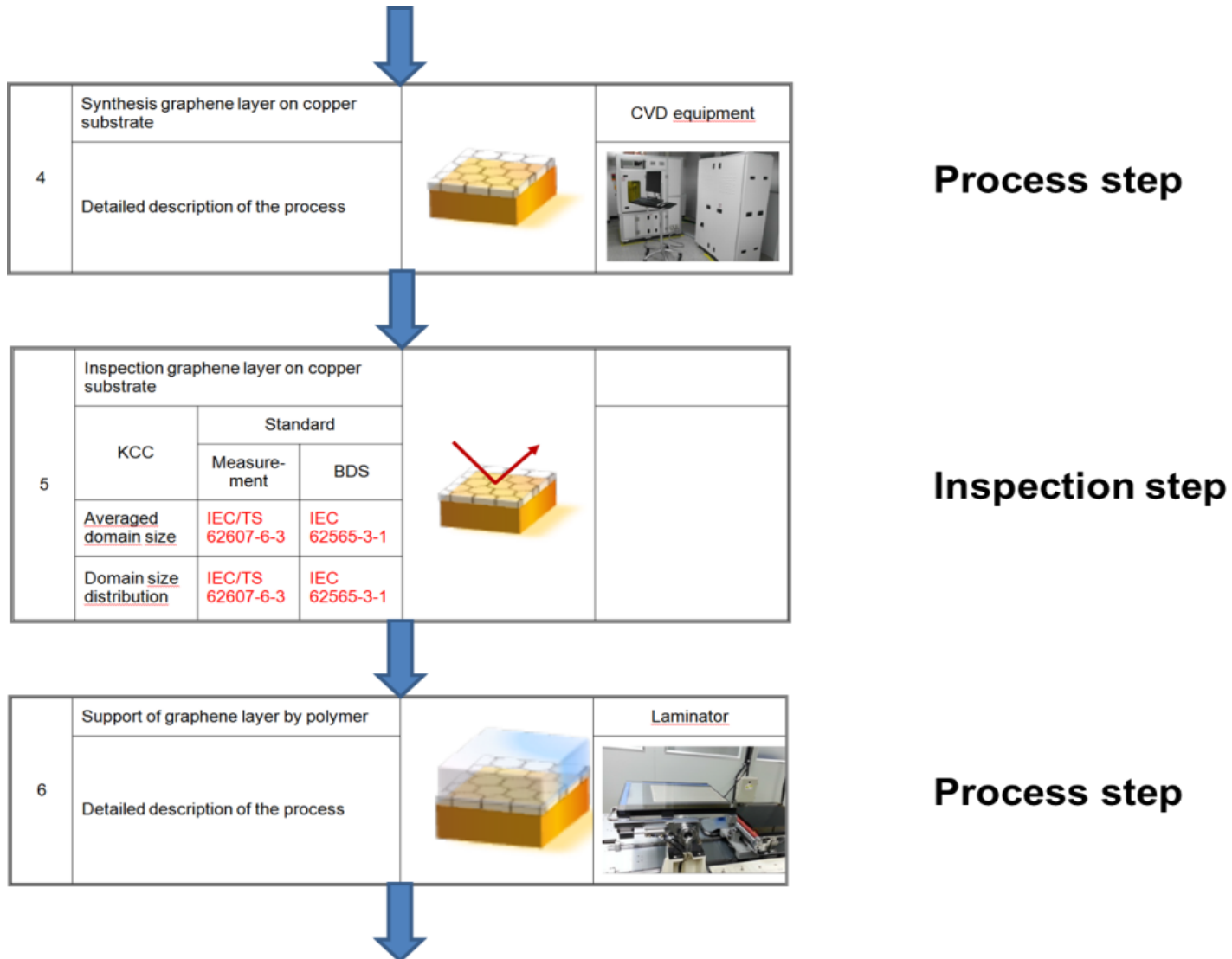
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Use case analysis: Value adding chain



- Availability of a Standard Operating Procedure (SOP) for each fabrication step is mandatory
- Measurement standards for Key Control Characteristics (KCC) are SOPs for controlling and inspection within a fabrication process chain

Use case analysis: Value adding chain





Operation of the secretariat IEC/TC 113:
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Ass. Secretary Prof. Dr. Werner Bergholz (ISC),
Ass. Secretary Gerd Weking (ISC)

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